

Product Change Notice (PCN)

Subject: Qualify SFA (Korea) as alternative wafer sort location for Pinehurst, AW910T005-FWZNA

Publication Date: 12/4/2025

Effective Date: 3/14/2026

Revision Description:

Initial Release

Description of Change:

Renesas is adding SFA (Korea) as an alternate wafer sort location (CP1, CP2) for the Pinehurst product list that are currently wafer sorted at KYEC, Taiwan. This will allow flexibility to ship from either facility and provide increased capacity, flexibility, and shorter lead time to meet market demand. There is no change in the CP1 and CP2 wafer sort test processing flows for the Pinehurst devices. Probe cards and test programs are the same at all qualified facilities. The testing is fully compatible and transferable between the test facilities with no change to the test coverage.

From: Current wafer sort location KYEC

To: New wafer sort locations KYEC and SFA (Korea).

Affected Product List:

P8911-Y0B001FNG
P8911-Y0B001FNG8
P8911-Y0Z001FNG
P8911-Y0Z001FNG8
P8911-Y0Z901FNG
P8911-Y0Z901FNG8

Reason for Change:

To provide increased capacity.

Impact on Fit, Form, Function, Quality & Reliability:

The change will have no impact on the form, fit, function, quality, reliability, and compliance of the products.

Product Identification:

Traceability to the wafer sort location is available on request.

Qualification Status: *Electrical correlation completed successfully. Refer Appendix A*

Sample Availability Date: 1/1/2026

Device Material Declaration: Not applicable

Note:

1. Acknowledgement must be received by Renesas within 30 days or Renesas will consider the change as approved.
2. If timely acknowledgement is provided by Customer, then Customer shall have 90 days from the date of receipt of this PCN to make any objections to this PCN. If Customer fails to make objections to this PCN within 90 days of the receipt of the PCN then Renesas will consider the PCN changes as approved.
3. If customer cannot accept the PCN then customer must provide Renesas with a last time buy demand and purchase order.

For additional information regarding this notice, please contact idt-pcn@lm.renesas.com

Appendix A - Electrical Test Correlation Results

Qual Vehicle: AW910T005-FWZNA

Sample size: 2 Wafers with DPW of 3727

Descriptions	Existing Wafer Sort CP1 & CP2 (KYEC, Taiwan)	Alternate Wafer Sort CP1 & CP2 (SFA, Korea)
Prober	TSK UF3000	Opus3_SD from SEMICS
Probe Card	AW910T-X20 Pinehurst	AW910T-X20 Pinehurst
Docking Type	Direct docking	Direct docking
Tester Platform	IFlex	IFlex
Test Program	IDTP8911-Y0_AW910T005_1p01	IDTP8911-Y0_AW910T005_1p01
Test Site	20	20
Test Temperature	25C	25C
Wafer Sort Correlation Results	Passed	Passed
Parametric Test Correlation Results	Passed	Passed